Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
10/616,258	NAKANO ET AL.
Examiner	Art Unit
Seung C. Sohn	2878

Seung C. Sohn

	SEARCHED				
Class	Subclass	Date	Examiner		
250	551	6/23/2005	scs		
	214LS	1	1		
	214SW				
	227.11				
	227.24				
	239				
257	80-84				
	431-435				

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NO (INCLUDING SEARC)
	DATE	EXMR
EAST (see separate printout)	6/23/2005	scs